TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L^2 - π -MOSV)

2SK2313

Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4-V gate drive

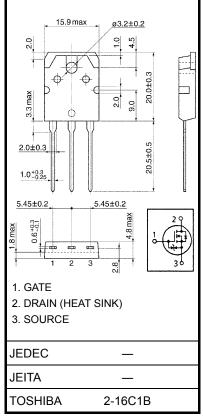
• Low drain-source ON resistance : R_{DS} (ON) = 8 m Ω (typ.) • High forward transfer admittance : $|Y_{fs}| = 60 \text{ S}$ (typ.) • Low leakage current : $I_{DSS} = 100 \text{ } \mu\text{A}$ (max) (VDS = 60 V)

• Low leakage current $I_{DSS} = 100 \,\mu\text{A} \,(\text{max}) \,(\text{V}_{DS} = 60 \,\text{V})$ • Enhancement mode $V_{th} = 0.8 \sim 2.0 \,\text{V} \,(\text{V}_{DS} = 10 \,\text{V}, \, \text{I}_{D} = 1 \,\text{mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	60	V	
Drain-gate voltage (R	_{GS} = 20 kΩ)	V_{DGR}	60	V	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	60	Α	
	Pulse (Note 1)	I _{DP}	240	Α	
Drain power dissipatio	n (Tc = 25°C)	P_{D}	150	W	
Single pulse avalanche	e energy (Note 2)	E _{AS}	1054	mJ	
Avalanche current		I _{AR}	60	Α	
Repetitive avalanche	energy (Note 3)	E _{AR}	15	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Unit: mm



Weight: 4.6 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	0.833	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	50	°C/W

Note 1: Ensure that the channel temperature does not exceed 150 $^{\circ}$ C.

Note 2: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 398 μ H, R_{G} = 25 Ω , I_{AR} = 60 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



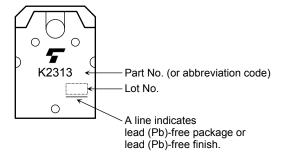
Electrical Characteristics (Ta = 25°C)

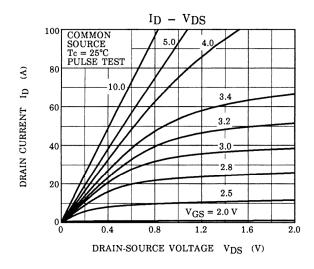
Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V	_	_	100	μA
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	60	_	_	V
Gate threshold v	voltage	V_{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V
Danie ON inter		R _{DS (ON)}	V _{GS} = 4 V, I _D = 30 A		12	15	m0
Drain-source ON resistance	V _{GS} = 10 V, I _D = 30 A		_	8	11	mΩ	
Forward transfer	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 30 A	40	60	_	S
Input capacitano	e	C _{iss}		_	5400	_	
Reverse transfer capacitance		C _{rss}	v _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	920	_	pF
Output capacitance		Coss		_	2600	_	
Switching time	Rise time	t _r	$V_{GS} = \frac{10V}{0V}$ $V_{GS} = \frac{10V}{0V}$ V_{OUT} $R_{L} = \frac{10V}{10V}$ $V_{DD} = 30V$ $V_{DD} = 30V$ $V_{DD} = 30V$	_	30	_	ns
	Turn-on time	t _{on}		_	60	_	
	Fall time	t _f		_	65	_	
	Turn-off time	t _{off}		_	220	_	
Total gate charge (Gate-source plus gate-drain)				170	_		
Gate-source charge		Q _{gs}	$V_{DD} \approx 48 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$		110		nC
Gate-drain ("miller") charge		Q _{gd}			60	_	

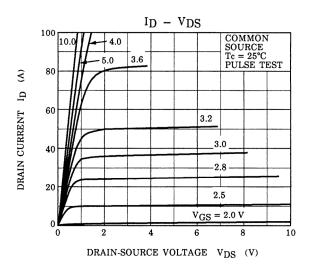
Source-Drain Ratings and Characteristics (Ta = 25°C)

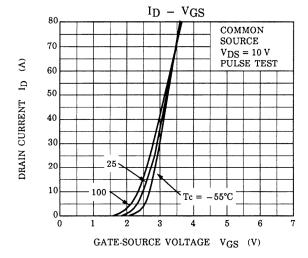
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	60	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	240	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 60 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 60 A, V _{GS} = 0 V	1	150	_	ns
Reverse recovered charge	Q _{rr}	dl _{DR} / dt = 50 A / μs	_	0.3	_	μC

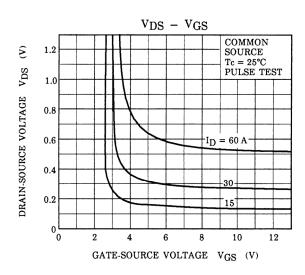
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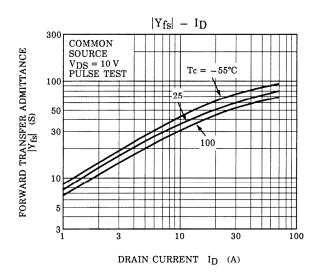


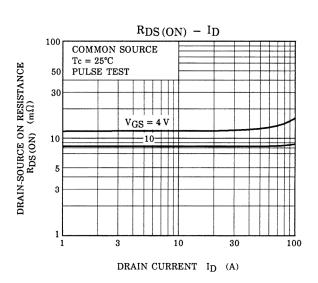




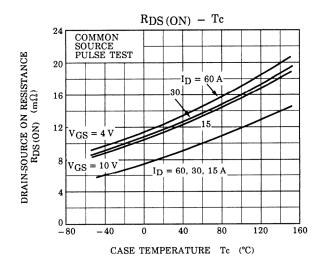


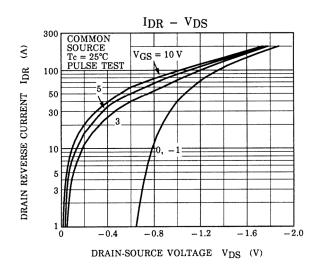


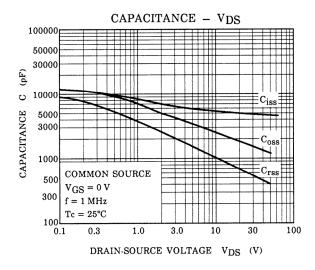


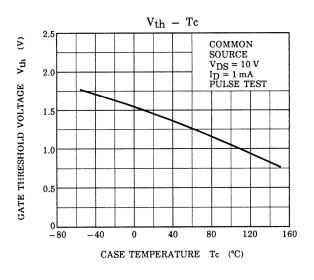


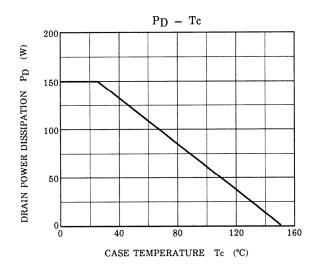
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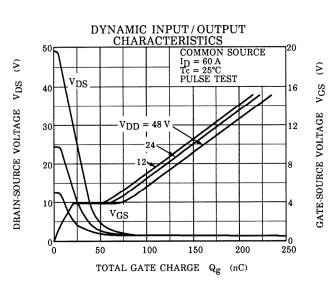


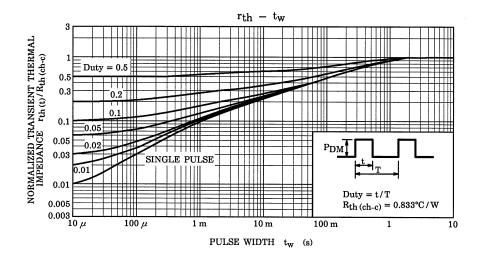


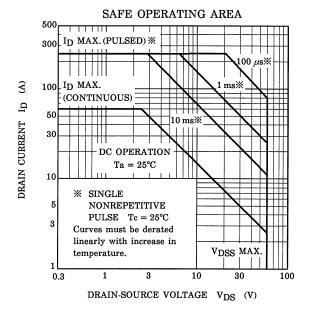


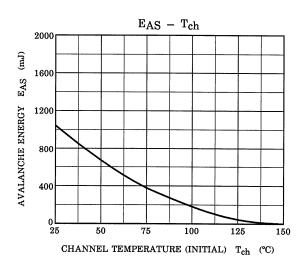


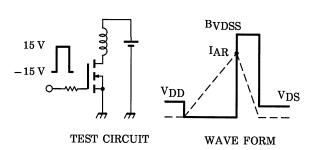












$$\begin{aligned} R_G &= 25 \ \Omega \\ V_{DD} &= 25 \ V, \ L = 398 \ \mu H \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right)$$

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